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Contents

٧	Authors
∨ii	Symposium Committees
ix	Conference Committee
xi	Introduction
xiii	Conference Organizers
	IRMMW-THZ TECHNOLOGIES AND ITS APPLICATIONS
11441 02	Non-uniformity correction technology of infrared thermal imager without shutter based on noise template [11441-1]
11441 03	Analytical method for studying terahertz vibrations in different ginseng [11441-2]
11441 04	Method for detecting blasting beads in cigarette filter [11441-3]
11441 05	Terahertz wave generation from laser-induced air plasma influenced by the external electric field $[11441-4]$
11441 06	Terahertz vortex beam generation based on complementary open rings metamaterial [11441-7]
11441 07	A simple approach to generate a monochromatic plate-like THz beam [11441-9]
11441 08	Temperature dependent terahertz spectroscopy of azithromycin dihydrate [11441-10]
11441 09	Research on scene-based IRFPA non-uniformity correction technology [11441-11]
11441 0A	Evaluation of outputted and leaked power for a micro-cavity laser in the terahertz region [11441-14]
11441 OB	Infrared target detection and tracking based on brain-inspired model and DNNs (Invited Paper) [11441-16]
11441 OC	Progress of THz traveling wave tube in IECAS (Invited Paper) [11441-18]
11441 OD	Enhanced terahertz imaging of electronic packaging materials with deconvolution algorithm [11441-19]

11441 OE	Flexible infrared electronic eyes for multispectral imaging with colloidal quantum dots [11441-20]
11441 OF	Qualitative detection of mycelium in cordyceps powder using terahertz time-domain spectroscopy [11441-24]
11441 0G	Causality relations in analysis of diffuse reflectance spectra obtained by infrared quantum cascade laser (Invited Paper) [11441-30]
11441 OH	Terahertz detection of chemical analytes using a hollow core photonic crystal fiber sensor [11441-31]
11441 01	Investigation of typical sartan pharmaceuticals by terahertz absorption spectroscopy and density functional theory $[11441-32]$
11441 OJ	Filtering path variable FDK (v-FDK) reconstruction algorithm for circular cone-beam CT [11441-41]
11441 OK	All optically-controlled multifunctional VO $_2$ memory device for terahertz waves $[11441-42]$
11441 OL	Particle filter tracking method for small infrared target based on combination of the high frequency feature [11441-44]
11441 OM	Research on terahertz non-destructive testing technology for internal defects of insulation layer $[11441-45]$

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Ackerman, Matthew M., 0E

An, Goufei, 0A
Cai, He, 0A
Chen, Qian, 09
Chen, Si-Chao, 0K
Du, Liang-Hui, 0K
Du, Yong, 0I
Feng, Shijia, 05
Fufurin, I. L., 0G
Golyak, Ig. S., 0G
Gu, Guohua, 09
Guo, Xin, 0C

Guyot-Sionnest, Philippe, 0E

Hao, Qun, 0B Hong, Zhi, 0l Hou, Yuan, 0M Huang, Meijiao, 08 Jiang, Xiaoyong, 09 Li, Haoyu, 0A Li, Jiang, 0K Li, Ting, 02

Li, Xiao-Nan, 06 Li, Ze-ren, 0J Ling, Dongxiong, 0D Liu, Haishun, 0F Liu, Jianjun, 0l Liu, Jingbo, 0D Liu, Shang-jian, 03 Liu, Wenxin, 0C Liu, Xiaoxu, 0A Luo, Qing, 0A Luo, Wenzhen, 04

Qi, Guo, 0M Rong, Kepeng, 0A Song, Haizhi, 0A

Morozov, A. N., 0G

Song, Yong, 0B Song, Zheyu, 0D Sui, Xiubao, 09 Svetlichnyi, S. I., 0G Tabalina, A. S., 0G

Tan, Bo-zhong, OJ Tan, Lijuan, OA Tang, Xin, OE

Teng, Feifei, OB Wang, Chen, OJ

Wang, Hongyan, 0L Wang, Kejia, 07 Wang, Meng, 0C Wang, Mengying, 0F Wang, Ping, 02

Wang, Rui, 04 Wang, You, 0A Wei, An-jie, 03

Wei, Dongshan, 0D Wu, Tong, 05 Wu, Yao, 0B

Xue, Jing, 0M Xue, Lu, 0H Yan, Miao, 0L Yan, Shihan, 0D

Yang, Jiao, 0A Yang, Qing-guo, 0J Yang, Xin, 0B Yu, Aoxue, 05

Yu, Xu-dong, 02 Yuan, Hong-Kuan, 0K Zhai, Zhao-Hui, 0K

Zhang, Cun-lin, 03, 05, 07, 08, 0F

Zhang, Liangliang, 05 Zhang, Yani, 0H Zhang, Zhaochuan, 0C

Zhang, Zhaochidan, OC Zhang, Zhenwei, 04, 07, 0M Zhang, Zhi-qiang, 02 Zhang, Ziming, 01

Zhang, Ziming, Oi Zhao, Chao, OC Zhao, Fei, OL Zhao, Guo-Zhong, 06

Zhao, Yuejin, 04, 07
Zhao, Yuejin, 04, 07
Zhao, Yufei, 0B
Zheng, Chan, 0D
Zhou, Jinyun, 0D
Zhou, Lu, 06
Zhou, Yu-mei, 02
Zhou, Zi-han, 03
Zhu, Li-Guo, 0K
Zhu, Lin, 09
Zhu, Yuyu, 0H
Zuo, Jian, 03, 08, 0F

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Introduction

With the mutual integration of IRMMW-THz Technologies and Its Applications, they have been mutually promoted and developed rapidly. Terahertz science and technology is not only due to it has not been fully explored, but due to its promising applications in spectroscopy, imaging, communications and nondestructive testing and so on. The tremendous demand has dramatically accelerated the research and development on the smaller terahertz emitter with high-power, the uncooled terahertz detector with high sensitivity, the portable and robust devices and systems with high speed. In recent years, many reliable new signal sources, detectors, functional devices and systems continue to emerge. Terahertz technology already plays a crucial role in aerospace, biological medicine, safety inspection, nondestructive testing, cultural relics protection and next generation wireless communication. At the same time, the research and development of small power terahertz radiation source, high sensitivity uncooled THz detector, a portable high-speed portable equipment and system is still the key bottlenecks in technology. We are glad to see this subject attracting an increasing amount of attention and interests. Joint effort made by academia and industry combined promotes terahertz science and technology development.

In this regard, IRMMW-THz Technologies and Its Applications of OIT 2019 was organized. The conference accepted over 35 presentations from different countries/areas of the world, which focused on the novel device, system and application of IRMMW-THz science and technology, and crossed many research disciplines including plasma, metamaterials, testing and calibration, sensors, imaging and biomedical technology. We also invited renowned scholars to present their cutting-edge, covering fundamental science such as, "Progress of THz traveling wave tube in IECAS" [11441-18] and, "Infrared target detection and tracking based on brain-inspired model and DNNs" [11441-16].

Cunlin Zhang Xi-Cheng Zhang Zhiming Huang

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